This listing of claims will replace all prior versions, and the listings of claims in the application:

Listing of Claims:

1. (Currently Amended) A method, comprising:

spinning a substrate having a film;

scanning an optical sensor across a path along a surface of the substrate;

sensing properties of the film with the optical sensor at a plurality of points along the path; and

generating a map of the film using information from the plurality of points along the path covering substantially an entire surface of the substrate;

wherein the generating of the map includes performing analysis of light reflected off the surface of the substrate and applying the results in one of a graphical representation or a text format representation.

2. (Original) The method of claim 1, wherein the path of the scanning is from the edge of the substrate to the center of the substrate affecting a path over the surface of the substrate.

3. (Original) The method of claim 1, wherein the path of the scanning is from the center of the substrate to the edge of the substrate affecting a reverse path over the surface of the substrate.

4. (Original) The method of claim 1, wherein the sensing properties of the film with the optical sensor includes the gathering of light reflected off the surface of the substrate.

5. (Cancelled)

6. (Original) The method of claim 1, further comprising;

scanning an inductive sensor across a path along the surface of the substrate.

7. (Original)The method of claim 6, wherein the path of the scanning is from the edge of the substrate to the center of the substrate affecting a path over the surface of the substrate.

8. (Original) The method of claim 6, wherein the path of the scanning is from the center of the substrate to the edge of the substrate affecting a reverse path over the surface of the substrate.

9. (Original) The method of claim 6, wherein the inductive sensor is capable of providing material properties of conductive materials on the surface of the substrate.

10. (Original) The method of claim 6, wherein the generating a map includes information obtained from the optical sensor and the inductive sensor provided in one of a graphical representation and a text format representation.

11. (Currently Amended) A method, comprising:

scanning an ~~optical~~ inductive sensor across a path defined along a surface of a substrate having a film when the substrate is spinning;

sensing properties of the film with the ~~optical~~ inductive sensor at a plurality of points along the path covering substantially an entire surface of the substrate; and

generating a map of the film using information from the plurality of points along the path.

12. (Original) The method of claim 11, wherein the path of the scanning is from the edge of the substrate to the center of the substrate affecting a path over the surface of the substrate.

13. (Original) The method of claim 11, wherein the path of the scanning is from the center of the substrate to the edge of the substrate affecting a reverse path over the surface of the substrate.

14.-18. (Cancelled)

19. (Currently Amended) The method of claim ~~16~~ 11, wherein the inductive sensor is capable of providing material properties of conductive materials on the surface of the substrate.

20. (Currently Amended) The method of claim ~~16~~ 11, wherein the generating a map includes information obtained from the optical sensor and the inductive sensor provided in one of a graphical representation and a text format representation.

21. (Currently Amended) A method, comprising:

scanning an optical sensor and an inductive sensor along a path defined over a region that is to define a surface of a substrate that can have a film, the substrate being configured to spin when present; and

sensing properties of the film at a plurality of points along the path covering substantially an entire surface of the substrate; and

generating a map of the film using information from the plurality of points along the path.

22. (Original) The method of claim 21, wherein the path of the scanning is from the edge of the substrate to the center of the substrate affecting a path over the surface of the substrate.

23. (Original) The method of claim 21, wherein the path of the scanning is from the center of the substrate to the edge of the substrate affecting a reverse path over the surface of the substrate.

24. (Original) The method of claim 21, wherein the sensing properties of the film with the optical sensor includes the gathering of light reflected off the surface of the substrate.

25. (Original) The method of claim 21, wherein the generating a map is accomplished by performing analysis of light reflected off the surface of the substrate and applying the results in one of a graphical representation and a text format representation.

26.-28. (Cancelled)

29. (Currently Amended) The method of claim ~~26~~ 21, wherein the inductive sensor is capable of providing material properties of conductive materials on the surface of the substrate.

30. (Currently Amended) The method of claim ~~26~~ 21, wherein the generating a map includes information obtained from the optical sensor and the inductive sensor provided in one of a graphical representation and a text format representation.

31.-41. (Cancelled)

42. (New) A method, comprising:

spinning a substrate having a film;

scanning an arm across a path from an edge of the substrate to the center of the substrate along a surface of the substrate, the arm having an optical sensor and an inductive sensor therein;

sensing properties of the film with the optical sensor and the inductive sensor at a plurality of points along the path covering substantially an entire surface of the substrate; and

generating a map of the film using information from the plurality of points along the path.

43. (New) The method of claim 42, wherein the generating of the map is accomplished by performing an analysis of information obtained from the optical sensor and the inductive sensor and displayed in one or both of a graphical representation and a text format representation.